

# Contents

<b>Pauli's Principle in Probe Microscopy</b> . . . . .	1
S.P. Jarvis, A.M. Sweetman, L. Kantorovich, E. McGlynn and P. Moriarty	
<b>Mechanical and Electrical Properties of Single Molecules</b> . . . . .	25
Thilo Glatzel	
<b>Atom Manipulation Using Atomic Force Microscopy at Room Temperature</b> . . . . .	49
Y. Sugimoto, M. Abe and S. Morita	
<b>A Considered Approach to Force Extraction from Dynamic Force Microscopy Measurements</b> . . . . .	63
Andrew Stannard and Adam M. Sweetman	
<b>Theoretical Challenges of Simultaneous nc-AFM/STM Experiments.</b> . .	81
P. Jelinek	
<b>Manipulation of Metal Nanoparticles on Insulating Surfaces</b> . . . . .	93
Clemens Barth	
<b>Imaging of Defects on Ge(001):H by Non-contact Atomic Force Microscopy</b> . . . . .	111
Bartosz Such, Marek Kolmer, Szymon Godlewski, Jakub Lis, Janusz Budzioch, Mateusz Wojtaszek and Marek Szymonski	
<b>Adsorption Structures of Amino Acids on Calcite(104)</b> . . . . .	119
Felix Kling, Markus Kittelmann and Angelika Kühnle	

<b>Origin of the KPFM Contrast in the Adsorption of a Triphenylene Derivative on KBr(001)</b> . . . . .	131
Antoine Hinaut, Florian Chaumeton, David Martrou and Sébastien Gauthier	
<b>Index</b> . . . . .	153

Imaging and Manipulation of Adsorbates Using Dynamic  
Force Microscopy

Proceedings from the AtMol Conference Series,

Nottingham, UK, April 16-17, 2013

Moriarty, P.; Gauthier, S. (Eds.)

2015, XX, 154 p. 62 illus., 40 illus. in color., Hardcover

ISBN: 978-3-319-17400-6